NEW AND/OR INTERESTING IN MICROSCOPY

- The Fourteenth Annual Short Course on Molecular Microspectroscopy is planned for 22 26 June, 1998 at Miami University. The short course presents the field of molecular microspectroscopy in terms of basic theory, applications, advances in the field and future developments. Participants are offered the opportunity to apply molecular microspectroscopy in small groups, discuss instrumentation with manufacturers who sponsor the short course, or talk with faculty and MML personnel about specific sampling problems. For further information, contact the Molecular Microspectroscopy Laboratory at Miami University: (513)529-2874, Fax: (513)529-7284
- Micscape and Microscopy-UK celebrates its second anniversary and notes that it has become the world's leading Amateur Microscopy organization. A world core of some 16 individuals contribute material on a regular basis either by producing articles for the Micscape Magazine, or by helping to deal with questions from the public, and other amateurs. And what an audience these 16 people share. In two years there has been over 40,000 visits to their front page alone, with all of the contributors material receiving requests to be viewed or read at a rate of over 30,000 items a week

Visit them at http://www.microscopy-uk.org.uk

RMC Announces its 5th Annual Materials Science Course: RMC, manufacturer of Ultramicrotomy, Histology and Cryo Products, will hold its 5th annual course titled: Using Ultramicrotomy in Materials Science: A Unique Approach to Problem Solving for EM. The course is a hands-on short course to be held in the late fall at the company's head-

Another Piece of The Puzzle

If you use an analytical SEM in your materials research then it's probable that your system comprises SEM/EDX/WDX/BSE which provides both surface & chemical information.

EBSP (crystallographic mapping) can provide a further level of important information including characterization of grain orientation boundaries and the relationship between texture and micro structure. Please call, fax or E-mail for our information package.



Ampersand International, Inc.

111 Twin Creek Lane • Freedom, PA 15042 Telephone (412) 742-4420 • Fax (412) 742-4430 E-Mail: amprsand@nauticom.net quarters in Tucson, AZ. Emphasis will be on the many specialized sample preparation techniques which make possible the ultramicrotomy of challenging materials. For more information, send an eMail to rmc@rmc-scientific.com or call Ann at (520)903-9366 x 251. Fax: (520)903-0132

As we wish that authors use their own style, we do not have a formal "Instruction for Authors", but only ask that the writing be clear, informative, and accurate.

Abbreviations and acronyms should be written out in full the first time they appear in a note or article. If they only appear once, then they should be written in full, and the abbreviation or acronym can be given in parentheses if it is widely used. Universally used abbreviations, such as "mL" for milliliters do not need to be written out.

"Microscopy 101" tips and hints are typically short (i.e., \sim <1,000 words). These notes can be "Here is how you do X", or for a stain or other protocol, a sentence or two on the value of the procedure. Explanations should be kept rather short - but as clear as necessary.

Longer material is published as articles, with the usual beginning-middle-end organization and while they can be of any length, we try to keep them under some 3,000 words plus illustrations. Illustrations, of any nature, are welcomein color or in black/white. Our normal policy is not to ask for financial help in using color images but, due to cost, only use them when the color is of real value.

While we greatly welcome articles and material from manufacturers and suppliers, such can not be product promotional in nature. A low key mention of products may be accepted. We reserve the right to determine the suitability of such articles and material.

Articles and material may be edited for space and/or language but will not be modified in substance without the approval of the author.

For the answers to other specific questions, contact either:

Don Grimes, Publisher at MicroToday@aol.com Phil Oshel, Technical Editor at poshel@hotmail.com



Diffraction Simulation & Analysis Software for the Macintosh®

2 Beam Dynamical Dislocation & Stacking Fault Simulation Full SAD Simulations with Spots, K-lines and Streaking

Lattice Calculation from Patterns

(just a few of the) Full Dynamic NEW FEATURES! CBED Simulation

Rapid Search of EDD,

Comparison of

PDF, and NBS/NIST Crystal Databases (purchased separately)

Diffractomer Spectra
~virtlabs/

http://www.Rt66.com/~virtlabs/ VIRTUAL LABORATORIES tel: 1-505-828-1640 • fax: 1-505-822-9759